



PATENT

IN THE UNITED STATES

PATENT AND TRADEMARK OFFICE

APPLICANT(S): Stephen W. Meeks et al.
APPLICATION NO.: 09/347,622
FILING DATE: July 2, 1999
TITLE: System For Simultaneously Measuring Thin Film Layer Thickness,
Reflectivity, Roughness, Surface Profile and Magnetic Pattern
EXAMINER: Tu T. Nguyen
GROUP ART UNIT: 2877
ATTY. DKT. NO.: 20830-04304

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Box Issue Fee, Commissioner For Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date shown below:

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LETTER TO THE CHIEF DRAFTSPERSON

SIR:

Enclosed are formal drawing containing twenty-five (25) sheets of Figures 1-31 for the above referenced application. The Office Action Summary mailed January 30, 2002 and the Notice of Allowance stated that the drawings as filed were accepted but the Notice of Draftsperson's Patent Drawing Review (attachment to Paper No. 11) indicated that the drawings should be formalized. While the Patent Office did not require these formal drawings, Applicants enclose them as a courtesy.

Respectfully submitted,
Stephen W. Meeks et al.

Dated: February 23, 2004

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